## E-Band Low Noise Downconverter SiP, 71 GHz to 76 GHz

## Data Sheet

## FEATURES

Conversion gain: 13 dB typical
Image rejection: $\mathbf{3 0} \mathbf{d B c}$ typical
Noise figure: 5 dB typical
Input IP3: 1 dBm typical
Input IP2: $\mathbf{2 8} \mathbf{d B m}$ typical
Input P1dB: $\mathbf{- 8}$ dBm typical
$6 \times$ LO leakage at RFIN: <-55 dBm typical
I/Q amplitude imbalance: 0.2 dB typical
I/Q phase imbalance: $5^{\circ}$ typical
Fully integrated, surface-mount, 34-terminal, $11 \mathrm{~mm} \times$ 13 mm LGA_CAV package

## APPLICATIONS

## E-band communication systems

High capacity wireless backhauls
Test and measurement
Aerospace and defense

FUNCTIONAL BLOCK DIAGRAM

outputs are provided for direct conversion applications. Alternatively, the outputs can be combined using an external $90^{\circ}$ hybrid and two external $180^{\circ}$ hybrids for single-ended applications.

The ADMV7410 comes in a fully integrated, surface-mount, 34-terminal, $11 \mathrm{~mm} \times 13 \mathrm{~mm}$, chip array small outline no lead cavity (LGA_CAV) package. The ADMV7410 operates over the $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ case temperature range.

## ADMV7410

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7/2019—Revision A: Initial Version

## SPECIFICATIONS

$\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}, \mathrm{IF}=1 \mathrm{GHz}$, LO power $=4 \mathrm{dBm}, \mathrm{VD} \_\mathrm{AMP}=+4 \mathrm{~V}$, VG_MIXER $=-1 \mathrm{~V}, \mathrm{VD} \_$MULT $=+1.5 \mathrm{~V}$, VD12_LNA $=$ +2 V , and VD34_LNA $=+4 \mathrm{~V}$, unless otherwise noted. Measurements performed as a downconverter with lower sideband selected and an external $90^{\circ}$ hybrid followed by two external $180^{\circ}$ hybrids at the IF ports, unless otherwise noted.

Table 1.

| Parameter | Symbol | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| OPERATING CONDITIONS |  |  |  |  |  |
| Frequency Range |  |  |  |  |  |
| RF |  | 71 |  | 76 | GHz |
| LO |  | 11.5 |  | 13 | GHz |
| IF Output |  | DC |  | 2 | GHz |
| LO Drive Level Range |  | 0 | 4 | 8 | dBm |
| PERFORMANCE |  |  |  |  |  |
| Conversion Gain |  | 7 | 13 | 20 | dB |
| Gain Flatness |  |  | 2 |  | dB |
| Image Rejection |  | 15 | 30 |  | dBC |
| Input Power for 1 dB Compression (Input P1dB) |  | -13 | -8 |  | dBm |
| Input Third-Order Intercept (Input IP3) |  | -6 | 1 |  | dBm |
| Input Second-Order Intercept (Input IP2) |  | 15 | 28 |  | dBm |
| $6 \times$ LO Leakage at the RF Input Port (RFIN) |  |  | <-55 | -50 | dBm |
| I/Q Amplitude Imbalance |  |  | 0.2 | 3 | dB |
| I/Q Phase Imbalance |  | -10 | 5 | 10 | Degrees |
| Noise Figure |  |  | 5 | 8 | dB |
| Return Loss |  |  |  |  |  |
| RFIN |  |  | 10 |  | dB |
| LO Input Port (LOIN) |  |  | 10 |  | dB |
| Baseband Output Port ${ }^{1}$ |  |  | 10 |  | dB |
| DIFFERENTIAL BASEBAND OUTPUT PORT IMPEDANCE |  |  | 100 |  | $\Omega$ |
| LOIN PORT IMPEDANCE |  |  | 50 |  | $\Omega$ |
| POWER SUPPLY |  |  |  |  |  |
| DC Power Dissipation |  |  | 1 | 1.25 | W |
| Low Noise Amplifier Gate Voltage | VG12_LNA, VG34_LNA | -2 |  | 0 | V |
| Low Noise Amplifier Drain Voltage |  |  |  |  |  |
| First and Second Stage | VD12_LNA | 1.9 | 2 | 2.1 | V |
| Third and Fourth Stage | VD34_LNA | 3.8 | 4 | 4.2 | V |
| Multiplier Drain Voltage | VD_MULT | 1.42 | 1.5 | 1.58 | V |
| Multiplier Gate Voltage | VG_MULT | -2 |  | 0 | V |
| Mixer Gate Voltage | VG_MIX | -2 |  | 0 | , |
| Low Noise Amplifier Supply Current | $\mathrm{IVD12}^{\text {LNA }}$ and IVD34_LNA |  | 66 |  | mA |
| Amplifier Drain Current | IvD_AMP |  | 175 |  | mA |
| Multiplier Drain Current | Ivd_Mult |  | 80 |  | mA |

${ }^{1}$ Measurements taken without external hybrids at the IF ports.

## ABSOLUTE MAXIMUM RATINGS

Table 2.

| Parameter | Rating |
| :--- | :--- |
| VD_AMP | 4.5 V |
| VD_MULT | 3 V |
| VD12_LNA and VD34_LNA | 4.5 V |
| VG_AMP | -3 V to +0.2 V |
| VG_MULT | -3 V to +0.2 V |
| VG12_LNA and VG34_LNA | -3 V to +0.2 V |
| LO Drive | 10 dBm |
| Baseband Input (IF_IP, IF_IN, IF_QP, and IF_QN) | 4 dBm |
| IF Source and Sink Current | 3 mA |
| Nominal Junction Temperature (TA $=85^{\circ} \mathrm{C}$ ) | $137^{\circ} \mathrm{C}$ |
| Maximum Junction Temperature | $175^{\circ} \mathrm{C}$ |
| $\quad$ (to Maintain 3 Million Hours Mean Time to |  |
| $\quad$ Failure (MTTF)) | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| Operating Temperature Range | $-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $260^{\circ} \mathrm{C}$ |
| Maximum Peak Reflow Temperature for |  |
| $\quad$ Moisture Sensitivity Level 3 (MSL3) | $\mathrm{JESD22-A101} 1^{1,2,3}$ |
| Thermal Humidity Bias (THB) | $\mathrm{JESD} 22-\mathrm{A} 101^{1,3}$ |
| Thermal Humidity Storage (THS) |  |
| Electrostatic Discharge (ESD) Sensitivity | 250 V |
| $\quad$ Human Body Model (HBM) | 500 V |
| $\quad$ Field Induced Charged Device Model |  |
| $\quad$ (FICDM) |  |

${ }^{1}$ Samples subject to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: bake for 24 hours at $125^{\circ} \mathrm{C}$, unbiased soak for 192 hours at $30^{\circ} \mathrm{C}$ and $60 \%$ relative humidity (RH), and reflow of three passes through an oven with a peak temperature of $260^{\circ} \mathrm{C}$.
${ }^{2}$ Results valid for 400 mW of nominal dc power dissipation for all active devices. Analog Devices, Inc., recommends that users perform their own THB test for all other bias conditions.
${ }^{3}$ Valid for package vent hole solder sealed or unsealed during test.
Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

## THERMAL RESISTANCE

Thermal performance is directly linked to printed circuit board (PCB) design and operating environment. Careful attention to PCB thermal design is required.
$\theta_{\mathrm{JC}}$ is the junction to case (or die to package) thermal resistance.
Table 3. Thermal Resistance ${ }^{1}$

| Package Type | $\boldsymbol{\theta}_{\mathrm{Jc}}$ | Unit |
| :--- | :--- | :--- |
| CE-34-2 | 52.4 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

${ }^{1}$ Thermal impedance simulated values are based on a JEDEC 2S2P test board with $11 \mathrm{~mm} \times 13 \mathrm{~mm}$ thermal vias. Refer to JEDEC standard JESD51-2 for additional information.

## ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

## PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



Figure 2. Pin Configuration
Table 4. Pin Function Descriptions

| Pin No. | Mnemonic | Description |
| :---: | :---: | :---: |
| 1, 6 to 12, 14, 16, 17, 19, 21 to 23, 25, 27, 29, 31, 34 | GND | Ground Connections. These pins must be connected to RF and dc ground. |
| 2 | IF_IP | Positive IF In Phase Output. This pin is dc-coupled. When operation to dc is not required, block this pin externally using a series capacitor with a value chosen to pass the necessary frequency range. For operation to dc, this pin must not source or sink more than 3 mA of current or device malfunction and device failure may result. |
| 3 | IF_IN | Negative IF In Phase Output. This pin is dc-coupled. When operation to dc is not required, block this pin externally using a series capacitor with a value chosen to pass the necessary frequency range. For operation to dc, this pin must not source or sink more than 3 mA of current or device malfunction and device failure may result. |
| 4 | IF_QN | Negative IF Quadrature Output. This pin is dc-coupled. When operation to dc is not required, block this pin externally using a series capacitor with a value chosen to pass the necessary frequency range. For operation to dc, this pin must not source or sink more than 3 mA of current or device malfunction and device failure may result. |
| 5 | IF_QP | Positive IF Quadrature Output. This pin is dc-coupled. When operation to dc is not required, block this pin externally using a series capacitor with a value chosen to pass the necessary frequency range. For operation to dc, this pin must not source or sink more than 3 mA of current or device malfunction and device failure may result. |
| 13 | VD34_LNA | Drain Voltage for the Third and Fourth Stage Low Noise Amplifier. See Figure 75 for the recommended external components. |
| 15 | VG34_LNA | Gate Voltage for the Third and Fourth Stage Low Noise Amplifier. See Figure 75 for the recommended external components. |
| 18 | VD12_LNA | Drain Voltage for the First and Second Stage Low Noise Amplifier. See Figure 75 for the recommended external components. |
| 20 | VG12_LNA | Gate Voltage for the First and Second Stage Low Noise Amplifier. See Figure 75 for the recommended external components. |


| Pin No. | Mnemonic | Description |
| :--- | :--- | :--- |
| 24 | LOIN | VG_MULT | | LO Input. This pin is dc-coupled and matched to $50 \Omega$. |
| :--- |
| 26 |
| Gate Voltage for the LO Multiplier. See Figure 75 for the recommended |
| external components. |
| Drain Voltage for the LO Multiplier. See Figure 75 for the recommended |
| external components. |
| 30 |$\quad$ VD_MULT | Gate Voltage for the LO Amplifier. See Figure 75 for the recommended |  |
| :--- | :--- |
| external components. |  |
| Drain Voltage for the LO Amplifier. See Figure 75 for the recommended |  |
| external components. |  |
| 32 | VD_AMP |
| PORT 1 | VF_MIXER | | Gate Voltage for the Field Effect Transistor (FET) Mixer. See Figure 75 for |
| :--- |
| the recommended external components. |
| WR-12 Waveguide Port. This port is ac-coupled and matched to the |
| waveguide input impedance. |
| Exposed Pads. The exposed ground pads must be connected to RF and |
| dc ground. |

## INTERFACE SCHEMATICS

GND


Figure 3. GND Interface Schematic


Figure 4. IF_IP, IF_IN, IF_QN, IF_QP, and VG_MIXER Interface Schematic

VD12_LNA, VD34_LNA


Figure 5. VD12_LNA and VD34_LNA Interface Schematic


Figure 6. VG12_LNA and VG34_LNA Interface Schematic


Figure 7. VG_MULT, VD_MULT, VG_AMP, and VD_AMP Interface Schematic


Figure 8. RFIN Interface Schematic

## TYPICAL PERFORMANCE CHARACTERISTICS

$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{IF}=1 \mathrm{GHz}$, RFIN $=-20 \mathrm{dBm}$ combined, LO power $=+4 \mathrm{dBm}$, and lower sideband selected, unless otherwise noted.


Figure 9. Conversion Gain vs. RF Frequency over Temperature


Figure 10. Image Rejection vs. RF Frequency over Temperature


Figure 11. Input IP3 vs. RF Frequency over Temperature


Figure 12. Conversion Gain vs. RF Frequency over LO Power


Figure 13. Image Rejection vs. RF Frequency over LO Power


Figure 14. Input IP3 vs. RF Frequency over LO Power


Figure 15. Input IP2 vs. RF Frequency over Temperature


Figure 16. Amplitude Imbalance vs. RF Frequency over Temperature


Figure 17. Phase Imbalance vs. RF Frequency over Temperature


Figure 18. Input IP2 vs. RF Frequency over LO Power


Figure 19. Amplitude Imbalance vs. RF Frequency over LO Power


Figure 20. Phase Imbalance vs. RF Frequency over LO Power


Figure 21. Noise Figure vs. RF Frequency over Temperature


Figure 22. Input P1dB vs. RF Frequency over Temperature


Figure 23. Noise Figure vs. RF Frequency over LO Power
$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{IF}=0.1 \mathrm{GHz}$, RFIN $=-20 \mathrm{dBm}$ combined, LO power $=+4 \mathrm{dBm}$, and lower sideband selected, unless otherwise noted.


Figure 24. Conversion Gain vs. RF Frequency over Temperature


Figure 25. Image Rejection vs. RF Frequency over Temperature


Figure 26. Input IP3 vs. RF Frequency over Temperature


Figure 27. Conversion Gain vs. RF Frequency over LO Power


Figure 28. Image Rejection vs. RF Frequency over LO Power


Figure 29. Input IP3 vs. RF Frequency over LO Power


Figure 30. Input IP2 vs. RF Frequency over Temperature


Figure 31. Amplitude Imbalance vs. RF Frequency over Temperature


Figure 32. Phase Imbalance vs. RF Frequency over Temperature


Figure 33. Input IP2 vs. RF Frequency over LO Power


Figure 34. Amplitude Imbalance vs. RF Frequency over LO Power


Figure 35. Phase Imbalance vs. RF Frequency over LO Power


Figure 36. Noise Figure vs. RF Frequency over Temperature


Figure 38. Noise Figure vs. RF Frequency over LO Power


Figure 37. Input P1dB vs. RF Frequency over Temperature
$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{IF}=0.5 \mathrm{GHz}$, RFIN $=-20 \mathrm{dBm}$ combined, LO power $=+4 \mathrm{dBm}$, and lower sideband selected, unless otherwise noted.


Figure 39. Conversion Gain vs. RF Frequency over Temperature


Figure 40. Image Rejection vs. RF Frequency over Temperature


Figure 41. Input IP3 vs. RF Frequency over Temperature


Figure 42. Conversion Gain vs. RF Frequency over LO Power


Figure 43. Image Rejection vs. RF Frequency over LO Power


Figure 44. Input IP3 vs. RF Frequency over LO Power


Figure 45. Input IP2 vs. RF Frequency over Temperature


Figure 46. Amplitude Imbalance vs. RF Frequency over Temperature


Figure 47. Phase Imbalance vs. RF Frequency over Temperature


Figure 48. Input IP2 vs. RF Frequency over LO Power


Figure 49. Amplitude Imbalance vs. RF Frequency over LO Power


Figure 50. Phase Imbalance vs. RF Frequency over LO Power


Figure 51. Noise Figure vs. RF Frequency over Temperature


Figure 52. Input P1dB vs. RF Frequency over Temperature


Figure 53. Noise Figure vs. RF Frequency over LO Power
$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{IF}=2 \mathrm{GHz}$, RFIN $=-20 \mathrm{dBm}$ combined, LO power $=+4 \mathrm{dBm}$, and lower sideband selected, unless otherwise noted.


Figure 54. Conversion Gain vs. RF Frequency over Temperature


Figure 55. Image Rejection vs. RF Frequency over Temperature


Figure 56. Input IP3 vs. RF Frequency over Temperature


Figure 57. Conversion Gain vs. RF Frequency over LO Power


Figure 58. Image Rejection vs. RF Frequency over LO Power


Figure 59. Input IP3 vs. RF Frequency over LO Power


Figure 60. Input IP2 vs. RF Frequency over Temperature


Figure 61. Amplitude Imbalance vs. RF Frequency over Temperature


Figure 62. Phase Imbalance vs. RF Frequency over Temperature


Figure 63. Input IP2 vs. RF Frequency over LO Power


Figure 64. Amplitude Imbalance vs. RF Frequency over LO Power


Figure 65. Phase Imbalance vs. RF Frequency over LO Power


Figure 66. Noise Figure vs. RF Frequency over Temperature


Figure 68. Noise Figure vs. RF Frequency over LO Power


Figure 67. Input P1dB vs. RF Frequency over Temperature

## RETURN LOSS AND $6 \times$ LO LEAKAGE



Figure 69. RF Return Loss vs. RF Frequency over Temperature LO Frequency $=11.8 \mathrm{GHz}$


Figure 70. IF Return Loss vs. IF Frequency over Temperature LO Frequency $=11.8 \mathrm{GHz}$


Figure 71. LO Return Loss vs. LO Frequency over Temperature


Figure 72. $6 \times$ LO Leakage at the RF Port over Temperature

## ADMV7410

## SPURIOUS PERFORMANCE

$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}, \mathrm{IF}=1 \mathrm{GHz}$, RFIN $=-20 \mathrm{dBm}$, and LO input $=+4 \mathrm{dBm}$, unless otherwise noted. Mixer spurious products are measured in dBc from the IF output power level single-ended for frequencies below 50 GHz , with all other IF ports terminated. Spur values are (M $\times R F$ ) $-(N \times$ LO). N/A means not applicable.
$M \times N$ Spurious Outputs, RF = 71 GHz, LO = 12 GHz

|  |  | N $\times$ LO |  |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 12 | 18 |
| $\mathbf{M} \times \mathbf{R F}$ | 0 | N/A | -35 | -55 | -56 | -73 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 1 | <-80 | <-80 | -75 | -66 | -85 | -34 | 0 | -34 | -67 | <-80 | <-80 |
|  | 2 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -74 | -31 | <-80 |
|  | 3 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -42 |
|  | 4 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 5 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |

$M \times N$ Spurious Outputs, $R F=73.5$ GHz, $L O=12.417$ GHz

|  |  | N $\times$ LO |  |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 12 | 18 |
| $\mathbf{M} \times \mathbf{R F}$ | 0 | N/A | -29 | -84 | -76 | -69 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 1 | <-80 | <-80 | -73 | -78 | -82 | -35 | 0 | -37 | -85 | <-80 | <-80 |
|  | 2 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -73 | -34 | <-80 |
|  | 3 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -96 |
|  | 4 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 5 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |

$M \times N$ Spurious Outputs, RF = 76 GHz, LO = 12.833 GHz

|  |  | $\mathrm{N} \times$ LO |  |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | 0 | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 12 | 18 |
| $\mathbf{M} \times \mathbf{R F}$ | 0 | N/A | -34 | -84 | -74 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 1 | <-80 | <-80 | <-80 | -74 | -85 | -91 | 0 | -90 | -83 | <-80 | <-80 |
|  | 2 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -65 | -33 | <-80 |
|  | 3 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | -97 |
|  | 4 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |
|  | 5 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 | <-80 |

## ADMV7410

## THEORY OF OPERATION

The ADMV7410 is a fully integrated $\mathrm{SiP}, \mathrm{I} / \mathrm{Q}$ low noise downconverter that consists of two functional blocks.
The RFIN port of the ADMV7410 is connected to the gallium arsenide (GaAs), low noise amplifier that consists of four stages of low noise amplification that feed into the second block.

The second block is a GaAs, I/Q downconverter with an integrated LO buffer and $6 \times$ multiplier. The $6 \times$ multiplier allows the use of a lower frequency range LO input signal, typically between 11.5 GHz and 13 GHz . The $6 \times$ multiplier is
implemented using a cascade of $3 \times$ and $2 \times$ multipliers. The LO buffer amplifiers are included on chip to allow a typical LO drive level of 4 dBm for typical performance. The LO path feeds a quadrature splitter followed by on-chip baluns that drive the I and Q mixer cores. The mixer cores comprise singly balanced passive mixers. The RF input of the $I$ and $Q$ mixers are then driven through an on-chip Wilkinson power splitter, which is then fed by the first block of the ADMV7410.

## APPLICATIONS INFORMATION POWER-UP BIAS SEQUENCE

The ADMV7410 functional blocks use active multiple amplifier and multiplier stages that all use depletion mode pseudomorphic high electron mobility transistors (pHEMTs). To ensure transistor damage does not occur, use the following power-up bias sequence and do not apply RF power to the device on the LO or IF ports unless otherwise noted:

1. Apply a - 2 V bias to VG_MULT, VG_AMP, VG12_LNA, and VG34_LNA.
2. Apply a -1 V bias to $\mathrm{VG}_{-}$MIXER.
3. Apply a 2 V bias to VD12_LNA.
4. Apply a 1.5 V bias to VD_MULT.
5. Apply a 4 V bias to VD_AMP and VD34_LNA.
6. Adjust VG_AMP between -2 V and 0 V to achieve a total IVD_AMP current of 175 mA .
7. Adjust VG12_LNA between -2 V and 0 V to achieve a total IVD12_LNA current of 22 mA .
8. Adjust VG34_LNA between -2 V and 0 V to achieve a total IVD34_LNA current of 44 mA .
9. Apply a LO input signal on the LO port and adjust VG_MULT between -2 V and 0 V to achieve a total Ivd_mult current of 80 mA .

## POWER-DOWN SEQUENCE

To power down the ADMV7410, take the following steps:

1. Apply a 0 V bias to VD_MULT, VD_AMP, VD12_LNA, and VD34_LNA.
2. Apply a 0 V bias to VG_MIXER.
3. Apply a 0 V bias to VG_MULT, VG_AMP, VG12_LNA, and VG34_LNA.

## LAYOUT

Solder the exposed pad on the underside of the ADMV7410 to a low thermal and electrical impedance ground plane. This pad is typically soldered to an exposed opening in the solder mask. Connect these ground vias to all other ground layers to maximize heat dissipation from the device package.
Figure 73 illustrates the recommended mechanical layout on the interface plate used to interface to the WR-12 waveguide opening of the ADMV7410. The recommended PCB land pattern footprint is shown in Figure 74.


Figure 73. Recommended Standard WR-12 Footprint




Figure 74. PCB Land Pattern Footprint

## TYPICAL APPLICATION CIRCUIT

Figure 75 shows the typical application circuit.


Figure 75. Typical Application Circuit

## OUTLINE DIMENSIONS



ORDERING GUIDE
$\left.\begin{array}{l|l|l|l}\hline \text { Model }^{\mathbf{1}} & \text { Temperature Range } & \text { Package Description } & \text { Package Option } \\ \hline \text { ADMV7410BCEZ } & -40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} & \begin{array}{l}34-\text { Terminal Chip Array Small Outline No Lead Cavity [LGA_CAV] } \\ \text { ADMV7410-EVALZ }\end{array} & \text { Evaluation Board }\end{array}\right]$ CE-34-2 $\quad$.

[^0]
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[^0]:    ${ }^{1} Z=$ RoHS Compliant Part.

